

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/705,884	SHIRAISHI ET AL.
	Examiner	Art Unit
	Paul D. Kim	3729

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Reviewed Parent Application 09/933,774 (US PAT. 6,690,551)	8/19/2005	PK
Text Search EAST/NPL (IEEE)	8/19/2005	PK
Updated Text Search EAST	11/2/2005	PK

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner